



The Testcenter facility 'LoRa® Test Lab' within IMST GmbH is recognized by the LoRa™ Alliance for testing in accordance to the LoRaWAN™ Specification V1.0.1

Report for Certification by Similarity according to LoRaWAN™ V1.0.1

for the Device

“ED1608RTS”

for the Customer

1M2M BV

Markus Ridder

Yavuz Turan

06. June 2017

Administrative Summary

Location: IMST GmbH, Test Centre, Kamp-Lintfort, Germany

Responsible Chief Check Engineer: Markus Ridder

Subject: Test of requirements for Certification by Similarity according to LoRaWAN™ Specification V1.0.1

Company and Contact Information:

1M2M BV

Korne 7

NL3453MJ de Meern, Netherlands

Checked Device: ED1608RTS

Firmware version: V1.0.7

Hardware version: V4.30

Original End-device identifier: ED1608 CO

Original End-device series:

LoRa Device Class: A

LoRaWAN Specification version: V1.0.1

Certification requirements: LoRa End Device Certification by Similarity V1.0

Frequency band(s): 868 MHz

Type of Certification by Similarity:

Case 3: Certification of an end-device variant from a certified end-device

Variant device differences to the referenced certified device:

- Same LoRa transceiver
- Same LoRa protocol SW version
- Same MCU Core
- Same Clock design and implementation

Brief description of the differences between the primary and the variant device

An external temperature sensor is connected to the device. And the application software on the device is different. Drivers etc. are the same.


Additional Checks: Comparison of FW implementation on plain code basis

Date: June 6nd, 2017


The Test Report, No. 6160348-A has the following conclusion:

The device fulfils the requirements.

Responsibility:


Yavuz Turan
Test Engineer

Approved:


Markus Ridder
Quality Engineer

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